

CDCLVP1204: Additive Jitter vs. Input Edge Rate

Test Conditions:

- CDCLVP1204 EVM
- Room Temperature
- 3.3V Supply Voltage
- 100 MHz frequency from Wenzel Oscillator (sine wave)
- Amplitude is varied to generate different edge rate signal
- Jitter is measured from 10 kHz to 20 MHz bandwidth

Input Edge Rate V/ns	Input Jitter fs	Output Jitter fs	Additive Jitter fs
0.86	31	108	103
0.72	32	110	105
0.69	35	119	113
0.59	28	128	125
0.47	33	141	137
0.35	30	170	167
0.23	52	228	221
0.11	150	402	373